

Search Notes

Application/Control No.

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Examiner

Young J. Kim

Applicant(s)/Patent under
Reexamination

HUANG ET AL.

Art Unit

1637

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
STIC Search of SEQ ID Numbers 13 and 14.	9/1/2006	YJK
Patent Databases (USPT, USPGP, EPO, JPO, DERWENT, IBM-TDB)	9/1/2006	YJK
Google search: GCGGTCCCAAAAGGGTCAGT and universal primer/tag	9/1/2006	YJK